

IKEA of Sweden AB TEST REPORT

SCOPE OF WORK: FCC Part 15 subpart B – EMC report

Model: LED1932R6

REPORT NUMBER 191000676SHA-001

ISSUE DATE October 22, 2019

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Report no. 191000676SHA-001

Applicant	:	IKEA of Sweden AB Box 702, SE-343 81 Älmhult, SWEDEN
Manufacturer	:	Same as applicant
Manufacturing site	:	LEEDARSON LIGHTING CO., LTD. Xingtai Industrial Park, Economic Development Zone of Changtai County, Zhangzhou City, Fujian Province, China

Summary

The equipment complies with the requirements according to the following standard(s) or Specification: **47CFR Part 15 (2018):** Radio Frequency Devices (Subpart B)

ANSI C63.4 (2014): American National Standard for Methods of Measurement of Radio-Noise Emissions from Low-Voltage Electrical and Electronic Equipment in the Range of 9 kHz to 40 GHz

PREPARED BY:

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Reviewer

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Revision History

Report No.	Version	Description	Issued Date
191000676SHA-001	Rev. 01	Initial issue of report	October 22, 2019



Measurement result summary

TEST ITEM	FCC REFERANCE	TEST RESULT	NOTE
Conducted emission	15.107	Pass	
Radiation emission	15.109	Pass	

Notes: 1: NA =Not Applicable

2. Determination of the test conclusion is based on IEC Guide 115 in consideration of measurement uncertainty.

3: Additions, Deviations and Exclusions from Standards: None.

Total Quality. Assured.

GENERAL INFORMATION 1

1.1 Description of Equipment Under Test (EUT)

Product Name	:	Self-ballasted LED lamps
Type/Model	:	LED1932R6
Description of EUT	:	We tested it, and listed the worst data.
Rating	:	AC 120V, 60Hz, 5.5W, 75mA, with E26 lamp cap
Brand name	:	IKEA
Category of EUT	:	Class B
EUT type	:	∑ Table top ☐ Floor standing
Sample received date	:	October 11, 2019
Sample identification No.	:	0191011-12
Date of test	:	October 11, 2019

Total Quality. Assured.

1.2 Description of Test Facility

Name	:	Intertek Testing Services Shanghai	
Address	:	Building 86, No. 1198 Qinzhou Road(North), Shanghai 200233, P.R. China	
Telephone	:	86 21 61278200	
Telefax	:	86 21 54262353	
The test facility is recognized, certified, or accredited by these organizations		CNAS Accreditation Lab Registration No. CNAS L0139 FCC Accredited Lab Designation Number: CN1175 IC Registration Lab CAB identifier.: CN0051 VCCI Registration Lab Registration No.: R-14243, G-10845, C-14723, T-12252 A2LA Accreditation Lab Certificate Number: 3309.02	

2 TEST SPECIFICATIONS

2.1 Standards or specification

47CFR Part 15 (2017): Radio Frequency Device: Subpart B

ANSI C63.4 (2014): Interim Standard for Methods of Measurement of Radio-Noise Emissions from Low-Voltage Electrical and Electronic Equipment in the Range of 9 kHz to 40GHz.

2.2 Mode of operation during the test

Within this test report, EUT was tested under all available operation modes and tested under its rating voltage and frequency. Other voltage and frequency is specified if used.

2.3 Test software list

Test Items	Software	Manufacturer	Version
Conducted emission	ESxS-K1	R&S	V2.1.0
Radiated emission	ES-K1	R&S	V1.71

2.4 Test peripherals list

Item No.	Name	Band and Model	Description

2.5 Record of climatic conditions

Test Item	Temperature (°C)	Relative Humidity (%)	Pressure (Kpa)
Conducted emission	24	42	101
Radiated Emission	24	42	101

Notes: NA =Not Applicable

Total Quality. Assured.

2.6 Instrument list

Condue	Conducted Emission / Disturbance Power / Tri-loop Test / CDN method				
Used	Equipment	Manufacturer	Туре	Internal no.	Due date
\boxtimes	Test Receiver	R&S	ESCS 30	EC 2107	2020-07-15
\boxtimes	A.M.N.	R&S	ESH2-Z5	EC 3119	2020-11-29
\boxtimes	Shielded room	Zhongyu	-	EC 2838	2020-01-13
Radiate	ed Emission				
Used	Equipment	Manufacturer	Туре	Internal no.	Due date
\boxtimes	Test Receiver	R&S	ESIB 26	EC 3045	2020-09-12
\boxtimes	Bilog Antenna	TESEQ	CBL 6112D	EC 4206	2020-06-10
\boxtimes	Semi-anechoic chamber	Albatross project	-	EC 3048	2020-07-31
Additic	onal instrument				
Used	Equipment	Manufacturer	Туре	Internal no.	Due date
\boxtimes	Therom- Hygrograph	ZJ1-2A	S.M.I.F.	EC 3326	2020-03-28
\boxtimes	Therom- Hygrograph	ZJ1-2A	S.M.I.F.	EC 3783	2020-02-28
\boxtimes	Pressure meter	YM3	Shanghai Mengde	EC 3320	2020-07-01



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2.7 Measurement Uncertainty

Measurement	Frequency	Expanded Uncertainty (k=2) (±)
Conducted emission at mains norts	9kHz ~ 150kHz	3.71 dB
Conducted emission at mains ports	150kHz ~ 30MHz	3.31 dB
Radiated Emissions up to 1 GHz	30MHz ~ 1GHz	5.04 dB
Dedicted Emissions above 1 CUI	1GHz ~ 6GHz	4.97 dB
Radiated Emissions above 1 GHz	6GHz ~ 18GHz	5.29 dB

3 Conducted emission

Test result: PASS

3.1 Limits

3.1.1 Limits for conducted emission of class A device

Frequency range	Limits dB(μV)		
(MHz)	Quasi-peak	Average	
0.15 ~ 0.5	79	66	
0.5 ~ 30	73	60	
Note: If the limit for the measur	Note: If the limit for the measurement with the average detector is met when using a receiver with a		
quasi-peak detector, the equipment under test shall be deemed to meet both limits and the			
measurement using the r	eceiver with an average detector ne	eed not be carried out.	

3.1.2 Limits for conducted emission of class B device

Frequency range	Limits dB(µV)			
(MHz)	Quasi-peak	Average		
0.15 ~ 0.5	66 ~ 56 *	56 ~ 46 *		
0.5 ~ 5	56	46		
5 ~ 30	60	50		

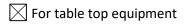
Note: 1. * Means the limit decreasing linearly with the logarithm of the frequency in the range 0.15MHz to 0.5MHz

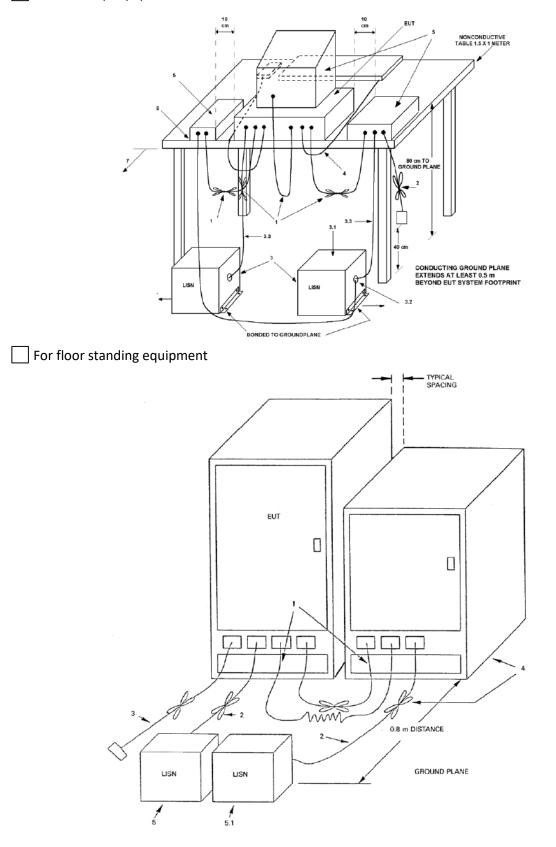
2. If the limit for the measurement with the average detector is met when using a receiver with a quasi-peak detector, the equipment under test shall be deemed to meet both limits and the measurement using the receiver with an average detector need not be carried out.

Total Quality. Assured.

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3.2 Test setup







Total Quality. Assured.

3.3 Test Setup and Test Procedure

Measurement was performed in shielded room, and instruments used were following clause 4 and clause 5 of ANSI 63.4.

Detailed test procedure was following clause 7.3 of ANSI 63.4.

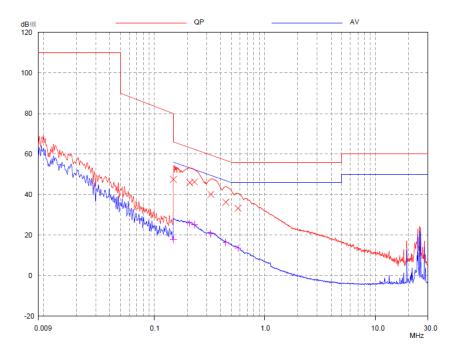
EUT arrangement and operation conditions were according to clause 6 and clause 7 of ANSI 63.4.

Frequency range 150kHz – 30MHz was checked and EMI receiver measurement bandwidth was set to 9 kHz.

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3.4 Test Protocol

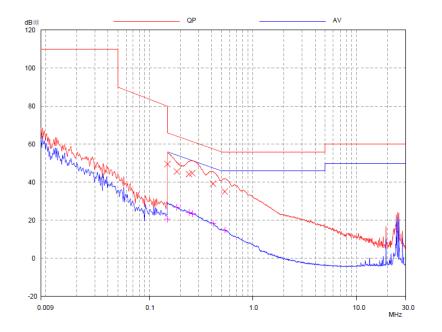
L line:



Final Measurement Results

Frequency	QP Level	QP Limit	QP Delta
MHz	dB礦	dB礦	dB
0.15	47.45	66.00	18.55
0.21129	45.93	63.15	17.22
0.23249	46.29	62.36	16.07
0.3275	40.15	59.51	19.36
0.44687	36.27	56.93	20.66
0.57666	33.27	56.00	22.73
Frequency	AV Level	AV Limit	AV Delta
MHz	dB礦	dB礦	dB
0.15	17.93	56.00	38.07
0.21129	25.89	53.15	27.26
0.23249	25.23	52.36	27.13
0.3275	20.69	49.51	28.82
0.44687	16.46	46.93	30.47
0.57666	13.56	46.00	32.44

N line:



Final Measurement Results

Frequency	QP Level	QP Limit	QP Delta
MHz	dB礦	dB礦	dB
0.15	49.59	66.00	16.41
0.18452	45.63	64.28	18.65
0.24194	44.31	62.03	17.72
0.25993	44.79	61.43	16.64
0.41264	39.27	57.59	18.32
0.53675	35.13	56.00	20.87
Frequency	AV Level	AV Limit	AV Delta
MHz	dB礦	dB礦	dB
0.15	20.71	56.00	35.29
0.18452	26.82	54.28	27.46
0.24194	24.04	52.03	27.99
0.25993	23.45	51.43	27.98
0.41264	18.37	47.59	29.22
0.53675	14.88	46.00	31.12

Remark: 1. Correct Factor = LISN Factor + Cable Loss, the value was added to Original Receiver Reading by the software automatically.

- 2. Corrected Reading = Original Receiver Reading + Correct Factor
- 3. Margin = Limit Corrected Reading
- 4. If the PK Corrected Reading is lower than AV limit, the AV test can be elided.

Example: Assuming LISN Factor = 10.00dB, Cable Loss = 2.00dB,

Original Receiver Reading = 10.00dBuV, Limit = 66.00dBuV. Then Correct Factor = 10.00 + 2.00 = 12.00dB; Corrected Reading = 10dBuV + 12.00dB = 22.00dBuV; Margin = 66.00dBuV - 22.00dBuV = 44.00dB.



4 Radiated emission

Test result: PASS

4.1 Radiated emission limits

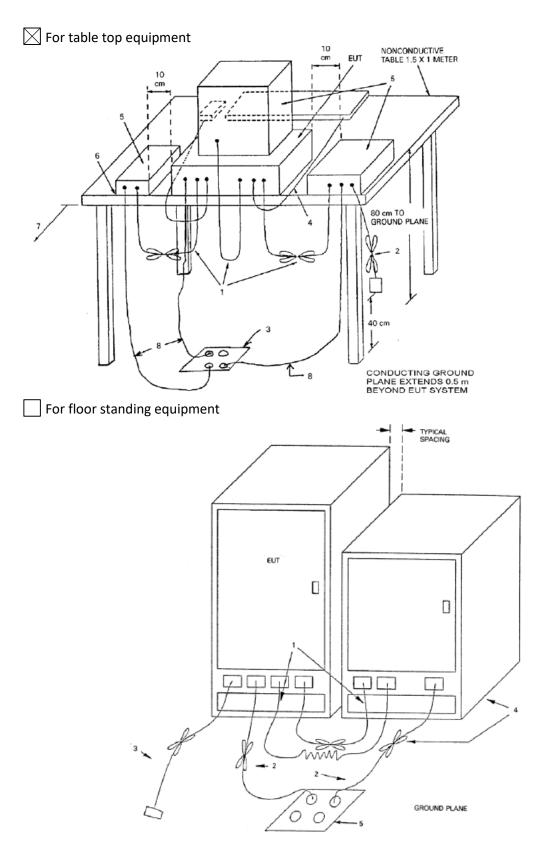
4.1.1 Limits for radiated emission of class A device

Frequency (MHz)	Permitted limit in dBμV/m (Quasi-peak) of Measurement Distance 10m	
30 ~ 88	39	
88 ~ 216	43.5	
216 ~ 960	46.4	
Above 960	49.5	
Note: for the measurement distance other than 3m and 10m, the limit is varied according to 20dB/10 decades.		

4.1.2 Limits for radiated emission of class B device

Frequency (MHz)	Permitted limit in dBμV/m (Quasi-peak) of Measurement Distance 3m		
30 ~ 88	40.0		
88 ~ 216	43.5		
216 ~ 960	46.0		
Above 960	54.0		
Note: for the measurement distance other than 3m and 10m, the limit is varied according to 20dB/10 decades.			

4.2 Block diagram and test set up



Total Quality. Assured.

4.3 Test Setup and Test Procedure

The measurement was performed in a semi-anechoic chamber.

The distance from EUT to receiving antenna is 3 meter.

Measurement was performed according to clause 4 and clause 5 of ANSI 63.4.

Test procedure was according to clause 8.3 of ANSI 63.4.

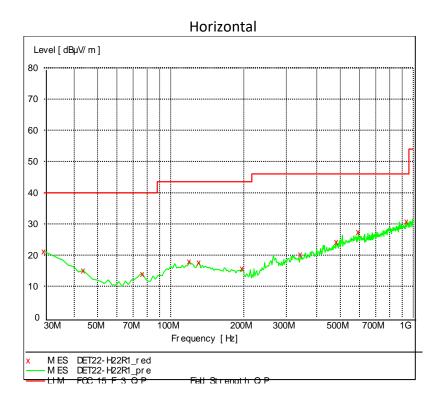
EUT arrangement and operate condition were according to clause 6 and clause 8 of ANSI 63.4.

The bandwidth setting on R&S Test Receiver was 120 kHz.

The required measurement frequency range was checked.

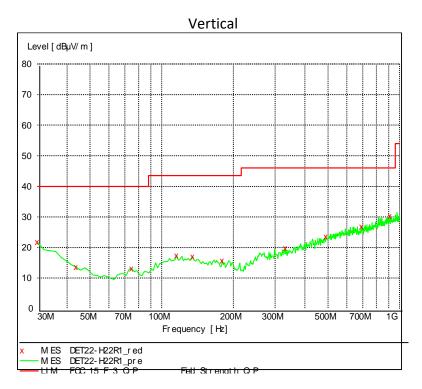
4.4 Test Protocol

Test Curve:



Frequency	<u>Level</u>	<u>Transd</u>	Limit	Margin
MHz	dBuV/m	dB d	BµV/m	dB
30.000000 43.607214 76.653307 119.418838 131.082164 197.174349 342.965932 482.925852 593.727455 939.739479	21.20 15.00 14.00 18.00 17.60 15.70 20.20 24.30 27.40 30.80	18.8 11.7 7.7 13.3 12.9 11.0 16.2 19.4 20.8 24.1	40.0 40.0 43.5 43.5 43.5 46.0 46.0 46.0 46.0	18.8 25.0 26.0 25.5 25.9 27.8 25.8 21.7 18.6 15.2





Frequency	<u>Level</u>	Transd	Limit	Margin
MHz	dBuV/m	dB d	BuV/m	dB
30.000000 43.607214 74.709419 115.531062 134.969940 179.679359 331.302605 490.701403 692.865731 912.525050	21.80 13.60 13.10 17.40 17.00 15.80 19.80 23.60 26.80 30.40	18.8 11.7 7.6 13.1 12.8 10.6 15.9 19.5 21.6 23.8	40.0 40.0 43.5 43.5 43.5 46.0 46.0 46.0	18.2 26.4 26.9 26.1 26.5 27.7 26.2 22.4 19.2 15.6

Remark: 1.Correct Factor = Antenna Factor + Cable Loss (+ Amplifier, for higher than 1GHz)

2. Corrected Reading = Original Receiver Reading + Correct Factor

3. Margin = Limit - Corrected Reading

4. If the PK Corrected Reading is lower than AV limit, the AV test can be elided.

Example: Assuming Antenna Factor = 30.20dB/m, Cable Loss = 2.00dB,

Gain of Preamplifier = 32.00dB, Original Receiver Reading = 10.00dBuV, limit = 40.00dBuV/m. Then Correct Factor = 30.20 + 2.00 - 32.00 = 0.20dB/m; Corrected Reading = 10dBuV + 0.20dB/m = 10.20dBuV/m; Margin = 40.00dBuV/m - 10.20dBuV/m = 29.80dB.

END of the report